CALL FOR PAPERS

The Conference focuses on all aspects of instrumentation and measurement science and technology – research, development and applications. The list of program topics includes but is not limited to:

**MEASUREMENT SCIENCE & EDUCATION**
- Theoretical foundations
- Quantities, units & standards
- Calibration & self-calibration
- Measurement uncertainty
- Methodology of teaching

**MEASUREMENT SYSTEMS**
- Automated test & diagnostics systems
- Fault-tolerant & resilient measurement systems
- Integrated & visual measurement systems
- Distributed measurement systems
- Autonomous measurement systems
- Non-invasive measurement systems
- Virtual measurement systems
- Measurement microsystems
- Human-computer interface

**MEASUREMENT-DATA ACQUISITION**
- Sensors & transducers
- A/D and D/A converters
- Analog & mixed signal processing
- Measurement signal generation
- Remote measurements & telemetry

**MEASUREMENT-DATA PROCESSING**
- Mathematical modeling of signals and systems
- Data preprocessing & postprocessing
- Digital signal processing
- Image processing & pattern recognition
- Inverse problems & signal reconstruction
- Signal detection & classification
- Sensor array processing
- Soft computing
- Measurement-data management

**MEASUREMENTS OF PHYSICAL QUANTITIES**
- Electrical & power measurements
- Dielectric & magnetic measurements
- Temperature, moisture & humidity measurements
- Mechanical measurements & material analysis
- Optical measurements
- Chemical & biological measurements

**MEASUREMENT APPLICATIONS**
- Robotics & industrial monitoring
- Automotive & transportation
- Avionics & aerospace
- Ships and marine technology
- Environmental monitoring
- Medicine & scientific research
- Security & biometrics
- Telecommunications

The program of IMTC 2007 will include special sessions related to hot topics such as measurements in nanotechnology, micro- and nano-optics measurements, new generations of sensors, etc. Moreover, IMTC 2007 will offer a day of tutorials on April 30, 2007 (Monday).

Potential authors are invited to submit extended abstracts via the IMTC website (http://ewh.ieee.org/soc/im/imtc/imtc2007). Each extended abstract (3 or 4 pages in English) should report results of the original research of theoretical or applied nature. It should, moreover, explain the significance of the contribution and contain a list of key references. It must be prepared according to the abstract preparation guidelines provided on the IMTC website. Check that website for detailed instructions, and follow the deadlines:
- October 6, 2006 – for the submission of extended abstracts,
- December 9, 2006 – for the notification of authors on the acceptance or rejection of extended abstracts,
- March 6, 2007 – for the submission of camera-ready full-text papers.

The extended abstracts will be reviewed by the Technical Program Committee. The authors of accepted abstracts, who submit the full-text papers, will be obliged to guarantee that they register for the Conference, pay registration fees, attend the Conference, and present their papers. A submitted paper will be published in the proceedings only if it is accompanied by the registration form(s) and the full member/non-member registration fees(s) for at least one of the authors (Student or Life Member fees are not sufficient). A full registration fee covers the publication of up to two accepted papers; each additional paper under the same registration requires a publication fee of US$ 50. The authors of papers, presented during IMTC 2007, will be allowed to submit updated and extended versions of those papers to the Special Issue of IEEE Transactions on Instrumentation & Measurement on IMTC 2007 to be published in 2008.

Further information will be provided on IMTC website: